(12) INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(19) World Intellectual Property Organization
International Bureau

(43) International Publication Date
15 September 2011 (15.09.2011)

PCT

(10) International Publication Number
WO 2011/112697 A1

(51) International Patent Classification:
*G01N 15/14* (2006.01)

(21) International Application Number:
PCT/US2011/027716

(22) International Filing Date:
9 March 2011 (09.03.2011)

(25) Filing Language: English

(26) Publication Language: English

(30) Priority Data:
61/312,616 10 March 2010 (10.03.2010) US

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(81) Designated States *(unless otherwise indicated, for every kind of national protection available)*: AE, AG, AL, AM, AO, AT, AU, AZ, BA, BB, BG, BH, BR, BW, BY, BZ, CA, CH, CL, CN, CO, CR, CU, CZ, DE, DK, DM, DO, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, GT, HN, HR, HU, ID, IL, IN, IS, JP, KE, KG, KM, KN, KP, KR, KZ, LA, LC, LK, LR, LS, LT, LU, LY, MA, MD, ME, MG, MK, MN, MW, MX, MY, MZ, NA, NG, NI, NO, NZ, OM, PE, PG, PH, PL, PT, RO, RS, RU, SC, SD, SE, SG, SK, SL, SM, ST, SV, SY, TH, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, ZA, ZM, ZW.

(84) Designated States *(unless otherwise indicated, for every kind of regional protection available)*: ARIPO (BW, GH, GM, KE, LR, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European (AL, AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HR, HU, IE, IS, IT, LT, LU, LV, MC, MK, MT, NL, NO, PL, PT, RO, RS, SE, SI, SK, SM, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

**Published**:

— *with international search report (Art. 21(3))*

— *before the expiration of the time limit for amending the claims and to be republished in the event of receipt of amendments (Rule 48.2(h))*

(54) **Title**: GENERATING PULSE PARAMETERS IN A PARTICLE ANALYZER

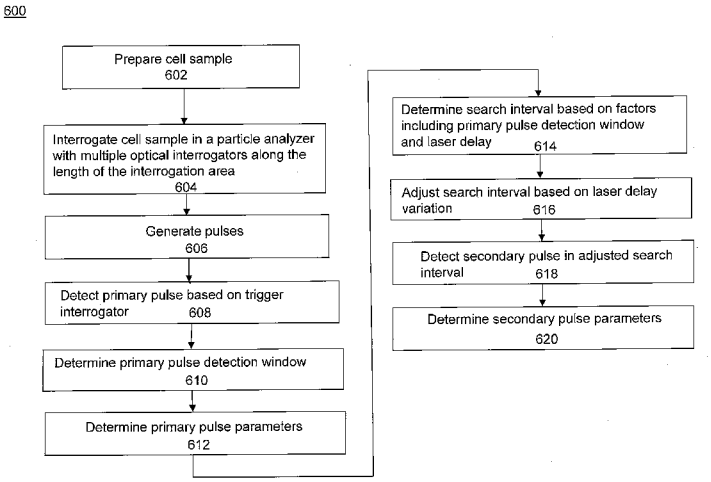



FIG. 6

(57) **Abstract**: A method is provided for generating measurement parameters for a particle sample in a particle analyzer. The method includes, interrogating the particle sample with a triggering interrogator and one or more secondary interrogators respectively positioned along a length of an interrogation area, generating respective pulses based upon the interrogation of a first particle from the particle sample, determining a primary pulse detection window based upon a triggering pulse, determining a search interval to find a secondary pulse based upon factors including the primary pulse detection window and a laser delay, adjusting the search interval for laser delay variation dynamically based on the interrogation of the first particle, identifying the secondary pulse in the adjusted search interval, and processing the secondary pulse to determine a peak value of the secondary pulse. Corresponding apparatus are also provided.

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